

# **Electrochemical Capacitance Voltage (ECV) Dopant Profiler**

## **Model: WEP CVP21**

The Wafer Profiler CVP21 is a handy tool to measure doping profiles in semiconductor layers by Electrochemical Capacitance Voltage Profiling (ECV-Profiling, CV-Profiling) in semiconductor research or production.

### **Process Capabilities**

- Ready to measure n and p type Silicon
- Substrate History: Phosphorus and Boron Diffused Samples
- Substrate Size : Preferably greater than 2 cm x 2 cm
- Concentration resolution :  $> 10^{12} \text{ cm}^{-3}$  to  $< 10^{21} \text{ cm}^{-3}$
- Depth resolution 1 nm to 100  $\mu\text{m}$

